



钜地半导体
Tudi Semiconductor

Product Specification

TUDI-ISL3259E

± 15kV ESD Protected, 100Mbps, 5V, PROFIBUS, Full Fail-Safe, RS-485/RS-422 Transceiver

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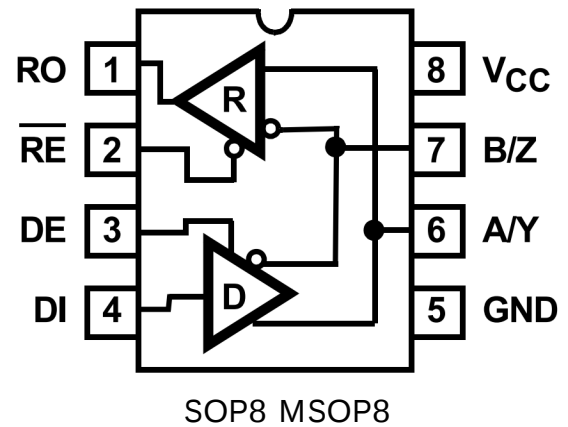
**semiconductor device
manufacturer**

- Design
- research and development
- production
- and sales



Features

- IEC61000 ESD protection on RS-485 I/O pins $\pm 15\text{kV}$
- Class 3 HBM ESD level on all other pins $>9\text{kV}$
- Large differential VOUT 2.8V into 54Ω Better noise immunity, or drive up to 6 terminations
- Very high data rate. up to 100Mbps
- 11/13ns (maximum) Tx/Rx propagation delays; 1.5ns (maximum) skew
- 1/5 unit load allows up to 160 devices on the bus
- Full fail-safe (open, shorted, terminated/undriven) receiver
- High Rx IOL to drive opto-couplers for isolated applications
- Hot plug - Tx and Rx outputs remain three-state during power-up
- Low quiescent supply current. 4mA
- Low current shutdown mode $1\mu\text{A}$
- -7V to $+12\text{V}$ common mode input voltage range
- Three-State Rx and Tx outputs
- Operates from a single $+5\text{V}$ supply
- Current limiting and thermal shutdown for driver overload protection
- Pb-free (RoHS compliant)



Applications

- PROFIBUS ®DP and FMS networks
- SCSI “ fast 40 ” drivers and receivers
- Motor controller/position encoder systems
- Factory automation
- Field bus networks
- Security networks
- Building environmental control systems
- Industrial/process control networks



Description

The ISL3259E is a $\pm 15\text{kV}$ IEC61000 ESD Protected, 5V powered, single transceiver that meets both the RS-485 and RS-422 standards for balanced communication. It also features the larger output voltage and higher data rate (up to 100Mbps) required by high speed PROFIBUS applications. The low bus currents ($+220\mu\text{A}/-150\mu\text{A}$) present a 1/5 unit load to the RS-485 bus. This allows up to 160 transceivers on the network without violating the RS-485 specification's load limit, and without using repeaters.

This transceiver requires a 5V supply, and delivers at least a 2.1V differential output voltage. This translates into better noise immunity (data integrity), longer reach, or the ability to drive up to six 120Ω terminations in "star" or other non-standard bus topologies.

SCSI applications benefit from the ISL3259E's low receiver and transmitter part-to-part skews. The ISL3259E is perfect for high speed parallel applications requiring simultaneous capture of large numbers of bits. The low bit-to-bit skew eases the timing constraints on the data latching signal.

Receiver (Rx) inputs feature a "Full Fail-Safe" design, which ensures a logic high Rx output if Rx inputs are floating, shorted, or terminated but undriven. Rx outputs feature high drive levels (typically $>30\text{mA}$ @ $V_{OL} = 1\text{V}$) to ease the design of optically isolated interfaces.

Hot plug circuitry ensures that the Tx and Rx outputs remain in a high impedance state while the power supply stabilizes.

Driver (Tx) outputs are short-circuit protected, even for voltages exceeding the power supply voltage. Additionally, on-chip thermal shutdown circuitry disables the Tx outputs to prevent damage if power dissipation becomes excessive.

Truth Table

TRANSMITTING				
INPUTS			OUTPUTS	
RE	DE	DI	B/Z	A/Y
X	1	1	0	1
X	1	0	1	0
0	0	X	High-Z	High-Z
1	0	X	High-Z*	High-Z*

NOTE: *Shutdown Mode



Truth Table

RECEIVING			
INPUTS			OUTPUT
RE	DE	A-B	RO
0	0	$V_{AB} \geq -0.05V$	1
0	0	$-0.05V > V_{AB} > -0.2V$	Undetermined
0	0	$V_{AB} \leq -0.2V$	0
0	0	Inputs Open/Shorted	1
1	1	X	High-Z
1	0	X	High-Z*

NOTE: *Shutdown Mode

Absolute Maximum Ratings

VCC to GND 7V

Input Voltages

DI, DE, RE -0.3V to 7V

Input/Output Voltages

A/Y, B/Z -9V to +13V

RO -0.3V to (VCC + 0.3V)

Short-circuit Duration

Y, Z Continuous

ESD Rating Refer to “Electrical Specifications”

Thermal Information

Thermal Resistance (Typical) θ_{JA} (°C/W)

8 Ld SOIC Package (Note 1) 105

8 Ld MSOP Package (Note 1) 140

Maximum Junction Temperature (Plastic Package) +150 °C Maximum Storage

Temperature Range -65 °C to +150 °C

Operating Conditions

Temperature Range -40 °C to +85 °C



NOTE: 1. θ_{JA} is measured with the component mounted on a high-effective thermal conductivity test board in free air.

Pin Descriptions

PIN	FUNCTION
RO	Receiver output: If $A-B \geq -50\text{mV}$, RO is high. If $A-B \leq -200\text{mV}$, RO is low. If A and B are unconnected(floating) or shorted, or connected to a terminated bus that is undriven, RO is high.
RE	Receiver output enable. RO is enabled when RE is low. RO is high impedance when RE is high. If the Rx enable function isn't required, connect RE directly to GND.
DE	Driver output enable. The driver outputs, Y and Z, are enabled by bringing DE high. They are high impedance when DE is low. If the Tx enable function isn't required, connect DE to Vcc through a 1k Ω or greater resistor.
DI	Driver input. A low on DI forces output Y low and output Z high. Similarly, a high on DI forces output Y high and output Z low.
GND	Ground connection. This is also the potential of the DFN thermal pad.
A/Y	$\pm 15\text{KV}$ IEC61000 ESD Protected RS-485, RS-422 level, noninverting receiver input and noninverting driver output. Pin is an input (A) if DEE=0; pin is an output (Y) if DE=1.
B/Z	$\pm 15\text{KV}$ IEC61000 ESD Protected RS-485, RS-422 level, inverting receiver input and inverting driver output. Pin is an input (B) if DE=0. Pin is an output (Z) if DE=1.
VCC	System power supply input (4.75V to 5.25V).
NC	No Connection.



Electrical Specifications

Test Conditions: $V_{CC} = 4.75V$ to $5.25V$; unless otherwise specified. Typical values are at $V_{CC} = 5V$, $T_A = +25^\circ C$, (Note 3).

PARAMETER	SYMBOL	TEST CONDITIONS	TEMP ($^\circ$)	MIN (Note 12)	TYP	MAX (Note 12)	UNITS
DC CHARACTERISTICS							
Driver Differential V_{OUT}	V_{OD}	No Load	Full	-	-	V_{CC}	
		$R_L=100\Omega$ (RS-422)(Figure 1A)	Full	2.6	3.4	-	V
		$R_L=54\Omega$ (RS-485)(Figure 1A)	Full	2.1	2.8	V_{CC}	V
		$R_L=60\Omega, -7V \leq V_{CM} \leq 12V$ (Figure 1B)	Full	1.9	2.7		V
Change in Magnitude of Driver Differential V_{OUT} for Complementary Output States	V_{OD}	$R_L=54\Omega$ or 100Ω (Figure 1A)	Full	-	0.01	0.2	V
Driver Common- Mode V_{OUT}	V_{OC}	$R_L=54\Omega$ or 100Ω (Figure 1A)	Full		2	3	V
Change in Magnitude of Driver Common-Mode V_{OUT} for Complementary Output States	V_{OC}	$R_L=54\Omega$ or 100Ω (Figure 1A)	Full	-	0.01	0.2	V
Logic Input High Voltage	V_{IH}	DI,DE,RE	Full	2	-		V
Logic Input Low Voltage	V_{IL}	DI,DE,RE	Full	-	-	0.8	V
Logic Input Current	I_{IN1}	DI=DE=RE=0V or V_{CC}	Full	-2	-	2	μA
Input Current(A/Y,B/ Z)	I_{IN2}	DE=0V, $V_{CC}=0V$ or $5.25V$	$V_{IN}=12V$	Full	-	220	μA
			$V_{IN}=-7V$	Full	-160		μA
Driver Short-Circuit Current, V_O =High or Low	I_{OSD1}	DE= V_{CC} , $-7V \leq V_Y$ or $V_Z \leq 12V$ (Note 5)	Full	-	-	± 250	mA



Electrical Specifications (Continued)

Test Conditions: $V_{CC} = 4.75V$ to $5.25V$; unless otherwise specified. Typical values are at $V_{CC} = 5V$, $T_A = +25^\circ C$, (Note 3).

PARAMETER	SYMBOL	TEST CONDITIONS	TEMP ($^\circ$)	MIN (Note 12)	TYP	MAX (Note 12)	UNIT S
Differential Capacitance	C_D	A/Y to B/Z	25	-	9	-	pF
Receiver Differential Threshold Voltage	V_{TH}	$-7V \leq V_{CM} \leq 12V$	Full	-200	-	-50	mV
Receiver Input Hysteresis	V_{TH}	$V_{CM}=0V$	25	-	28	-	mV
Receiver Output High Voltage	V_{OH}	$I_O = -8mA, V_{ID} = -50mV$	Full	$V_{CC}-0.5$	-		V
Receiver Output Low Voltage	V_{OL}	$I_O = +10mA, V_{ID} = -200mV$	Full	-	-	0.4	V
Receiver Output Low Current	I_{OL}	$V_{OL}=1V, V_{ID}=-200mV$	Full	25	40	-	mA
Three-State (High Impedance) Receiver Output Current	I_{OZR}	$0.4V \leq V_O \leq 2.4V$	Full	-1	0.015	1	μA
Receiver Input Resistance	R_{IN}	$-7V \leq V_{CM} \leq 12V$	Full	54	80	-	k Ω
Receiver Short-Circuit Current	I_{OSR}	$0V \leq V_O \leq V_{CC}$	Full	± 20	-	± 110	mA
SUPPLY CURRENT							
No-Load Supply Current(Note Z)	I_{CC}	$DI=DE=0V$ or V_{CC}	Full	-	2.6	4	mA
Shutdown Supply Current	I_{SHDN}	$DE=0V, RE=V_{CC}, DI=0V$ or V_{CC}	Full	-	0.05	1	μA
ESD PERFORMANCE							
RS-485 Pins(A/Y,B/Z)		IEC61000-42,Air-Gap Discharge Method	25	-	± 15	-	kV
		IEC61000-4-2,Contact Discharge Method	25	-	± 8	-	kV
		Human Body Model,From Bus Pins to GND	25	-	± 16.5	-	kV



Electrical Specifications (Continued)

Test Conditions: $V_{CC} = 4.75V$ to $5.25V$; unless otherwise specified. Typical values are at $V_{CC} = 5V$, $T_A = +25^\circ C$, (Note 3).

PARAMETER	SYMBOL	TEST CONDITIONS	TEMP (°)	MIN (Note 12)	TYP	MAX (Note 12)	UNIT S
All Pins		HBM,per MIL-STD-883 Method 3015	25	-	>±9	-	kV
		Machine Model	25	-	>± 400	-	V
DRIVER SWITCHING CHARACTERISTICS							
Maximum Data Rate	f _{MAX}	V _{OD} ≥ ±1.5V,R _D =54Ω,C _L = 100pF(Figure 4)	Full	100	-	-	Mbps
Driver Differential Output Delay	t _{DD}	R _D =54Ω,C _D =50pF(Figure 2)	Full	-	8	12	ns
Driver Differential Output Skew	t _{SKEW}	R _D =54Ω,C _D =50pF(Figure 2)	Full		0.5	1.5	ns
Prop Delay Part-to- Part Skew	t _{SKP-P}	R _D =54Ω,C _D =50pF(Figure 2), (Note 8)	Full	-	-	4	ns
Driver Differential Rise or FallTime	t _{R,tF}	R _D =54Ω,C _D =50pF(Figure 2)	Full	2	5	8	ns
Driver Enable to Output High	t _{ZH}	R _L =110Ω,C _L =50pF,SW=GND (Figure 3),(Note 6)	Full	-	13	20	ns
Driver Enable to Output Low	t _{ZL}	R _L =110Ω,C _L =50pF,SW=V _{cc} (Figure 3),(Note 6)	Full	-	11	20	ns
Driver Enable Time Skew	t _{ENSKEW}	t _{ZH} (Y or Z)-t _{ZL} (Z or Y)	Full	-	2.5	-	ns
Driver Disable from Output High	t _{HZ}	R _L =110Ω,C _L =50pF,SW=GND (Figure 3)	Full	-	14	20	ns
Driver Disable from Output Low	t _{LZ}	R _L =110Ω,C _L =50pF,SW=V _{cc} (Figure 3)	Full		12	20	ns
Driver Disable Time Skew	t _{DISSKEW}	t _{HZ} (Y or Z)-t _{LZ} (Z or Y)	Full	-	3	-	ns
Time to Shutdown	t _{SHDN}	(Note 8)	Full	60	-	600	ns



Electrical Specifications (Continued)

Test Conditions: $V_{CC} = 4.75V$ to $5.25V$; unless otherwise specified. Typical values are at $V_{CC} = 5V$, $T_A = +25^{\circ}C$, (Note 3).

PARAMETER	SYMBOL	TEST CONDITIONS	TEMP ($^{\circ}$)	MIN (Note 12)	TYP	MAX (Note 12)	UNIT S
Driver Enable from Shutdown to Output High	$t_{ZH(SHDN)}$	$R_L = 110\Omega, C_L = 50pF$, $SW = GND$ (Figure 3), (Notes 11,12)	Full		-	1000	ns
Driver Enable from Shutdown to Output Low	$t_{ZL(SHDN)}$	$R_L = 110\Omega, C_L = 50pF, SW = V_{CC}$ (Figure 3),(Notes 8.9)	Full	-	-	1000	ns
RECEIVER SWITCHING CHARACTERISTICS							
Maximum Data Rate	f_{MAX}	$VID = \pm 1.5V$	Full	100	-	-	Mbps
Receiver Input to Output Delay	t_{PLH}, t_{PHL}	(Figure 5)	Full	-	9	13	ns
Receiver Skew $t_{pLH} - t_{pHL}$	t_{SKD}	(Figure 5)	Full	-	0	1.5	ns
Prop Delay Part-to-Part Skew	t_{SKP-P}	(Figure 5),(Note 11)	Full	-	-	4	ns
Receiver Enable to Output High	t_{ZH}	$R_L = 1k\Omega, C_L = 15pF, SW = GND$ (Figure 6),(Note 8)	Full	-	-	12	ns
Receiver Enable to Output Low	t_{ZL}	$R_L = 1k\Omega, C_L = 15pF, SW = V_{CC}$ (Figure 6),(Note 8)	Full	-		12	ns
Receiver Disable from Output High	t_{HZ}	$R_L = 1k\Omega, C_L = 15pF, SW = GND$ (Figure 6)	Full	-	-	12	ns
Receiver Disable from Output Low	t_{LZ}	$R_L = 1k\Omega, C_L = 15pF, SW = V_{CC}$ (Figure 6)	Full	-	-	12	ns
Time to Shutdown	t_{SHDN}	(Notes 9)	Full	60	-	600	ns
Receiver Enable from Shutdown to Output High	$t_{ZH(SHDN)}$	$R_L = 1k\Omega, C_L = 15pF, SW = GND$ (Figure 6),(Notes 8,10)	Full	-	-	1000	ns
Receiver Enable from Shutdown to Output Low	$t_{ZL(SHDN)}$	$R_L = 1k\Omega, C_L = 15pF, SW = V_{CC}$ (Figure 6),(Notes 8,10)	Full	-	-	1000	ns



NOTES:

3. All currents into device pins are positive; all currents out of device pins are negative. All voltages are referenced to device ground unless otherwise specified.
4. Supply current specification is valid for loaded drivers when $DE = 0V$.
5. Applies to peak current.
6. Because of the shutdown feature, keep $RE = 0$ to prevent the device from entering SHDN.
7. Because of the shutdown feature, the RE signal high time must be short enough (typically $<100ns$) to prevent the device from entering SHDN.
8. These ICs are put into shutdown by bringing RE high and DE low. If the inputs are in this state for less than $60ns$, the parts are guaranteed not to enter shutdown. If the inputs are in this state for at least $700ns$, the parts are guaranteed to have entered shutdown.
9. Keep $RE = VCC$, and set the DE signal low time $>700ns$ to ensure that the device enters SHDN.
10. Set the RE signal high time $>700ns$ to ensure that the device enters SHDN.
11. This is the part-to-part skew between any two units tested with identical test conditions (Temperature, V_{cc} , etc.).
12. Parts are 100% tested at $+25^{\circ}C$. Over-temperature limits are established by characterization and are not production tested.

Test Circuits and Waveforms

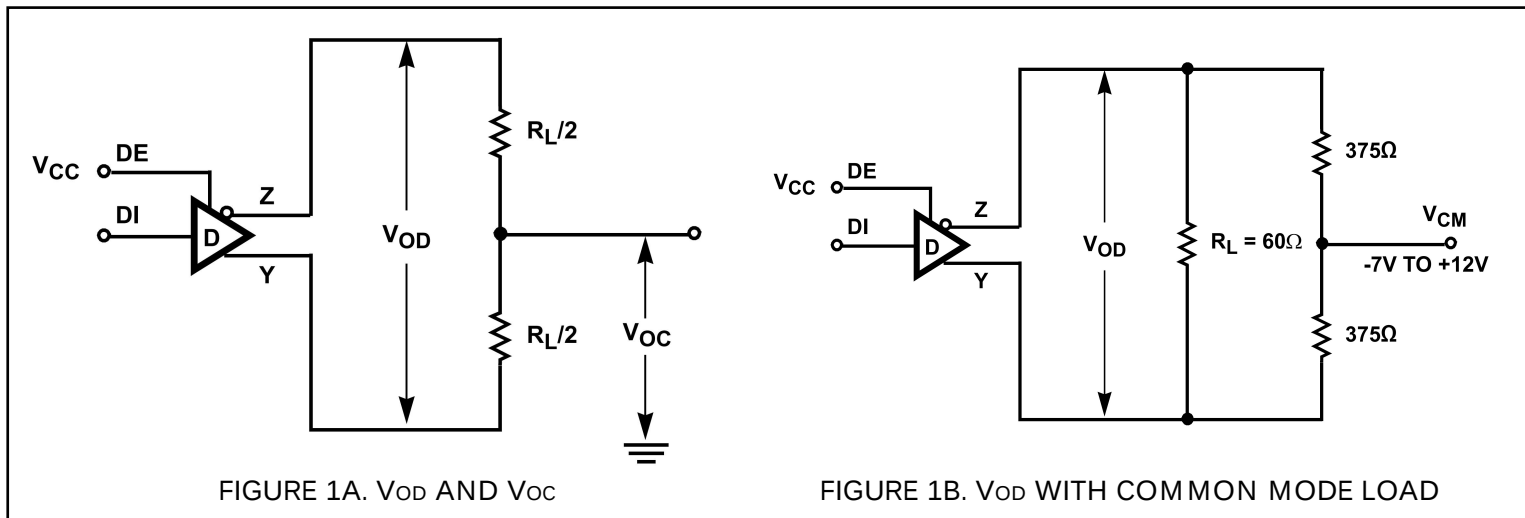


FIGURE 1. DC DRIVER TEST CIRCUITS



Test Circuits and Waveforms (Continued)

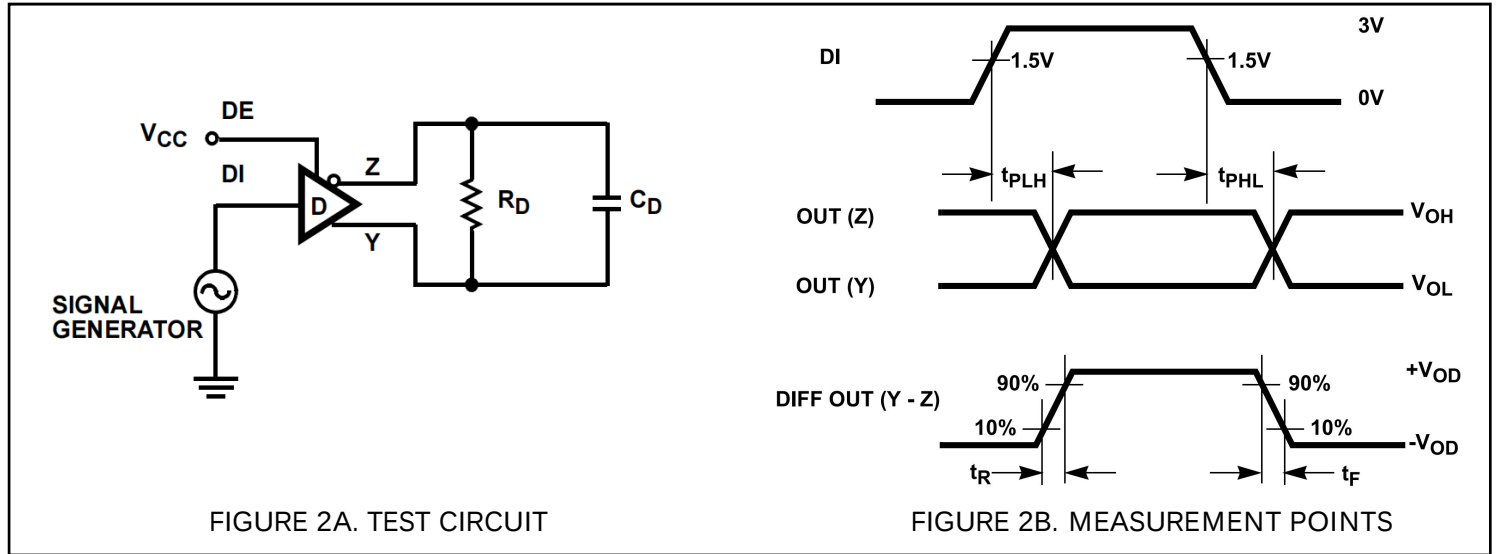


FIGURE 2. DRIVER PROPAGATION DELAY AND DIFFERENTIAL TRANSITION TIMES

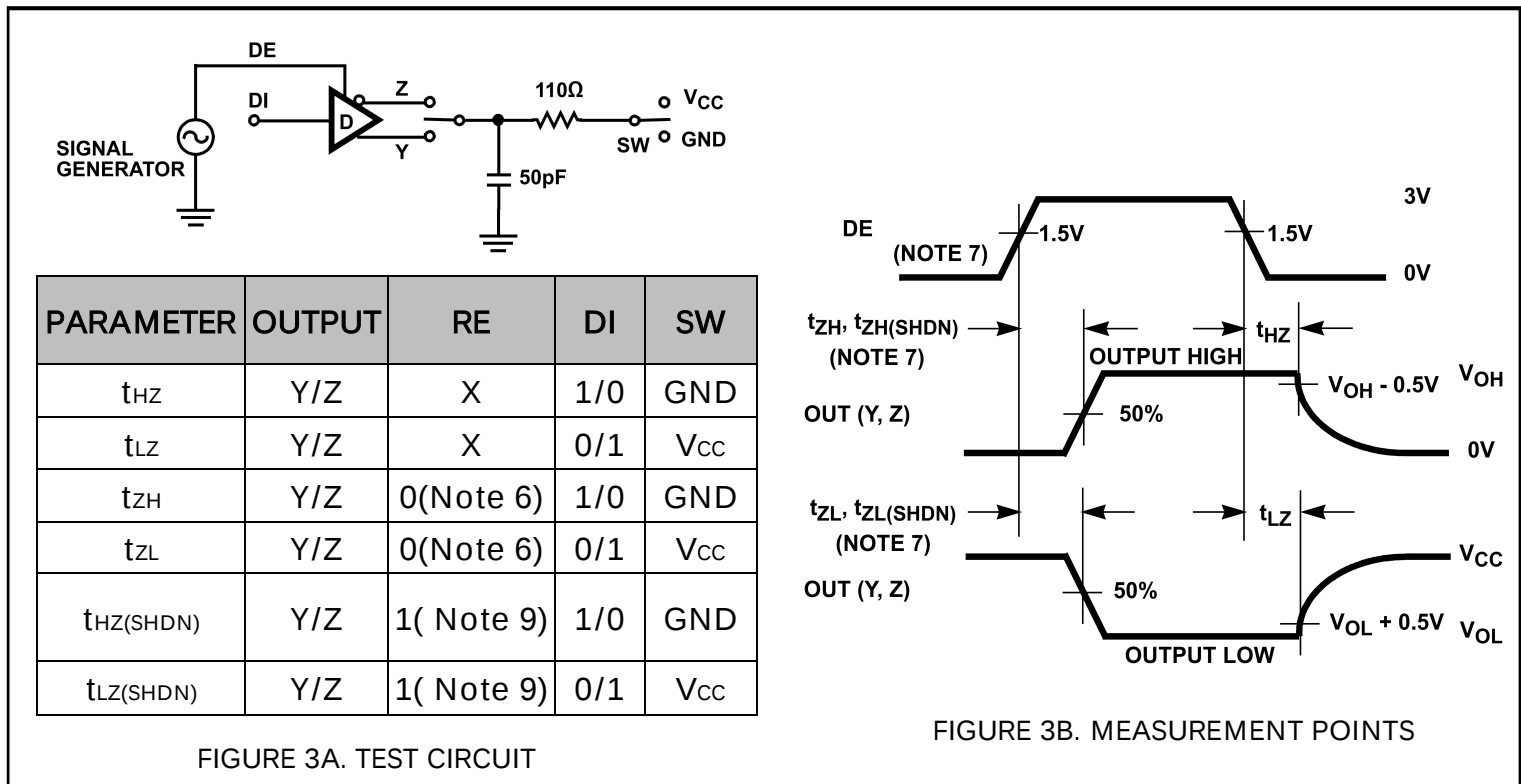


FIGURE 3. DRIVER ENABLE AND DISABLE TIMES



Test Circuits and Waveforms (Continued)

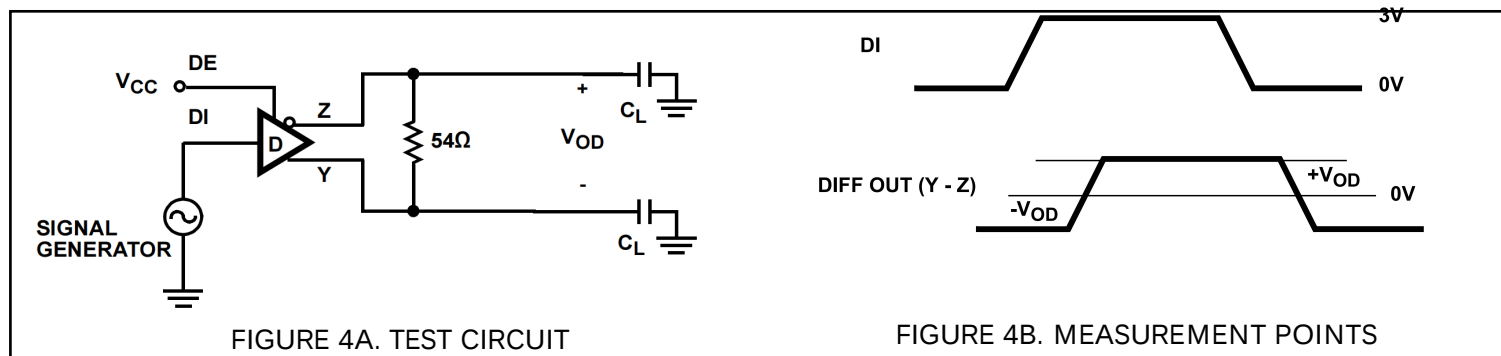


FIGURE 4. DRIVER DATA RATE

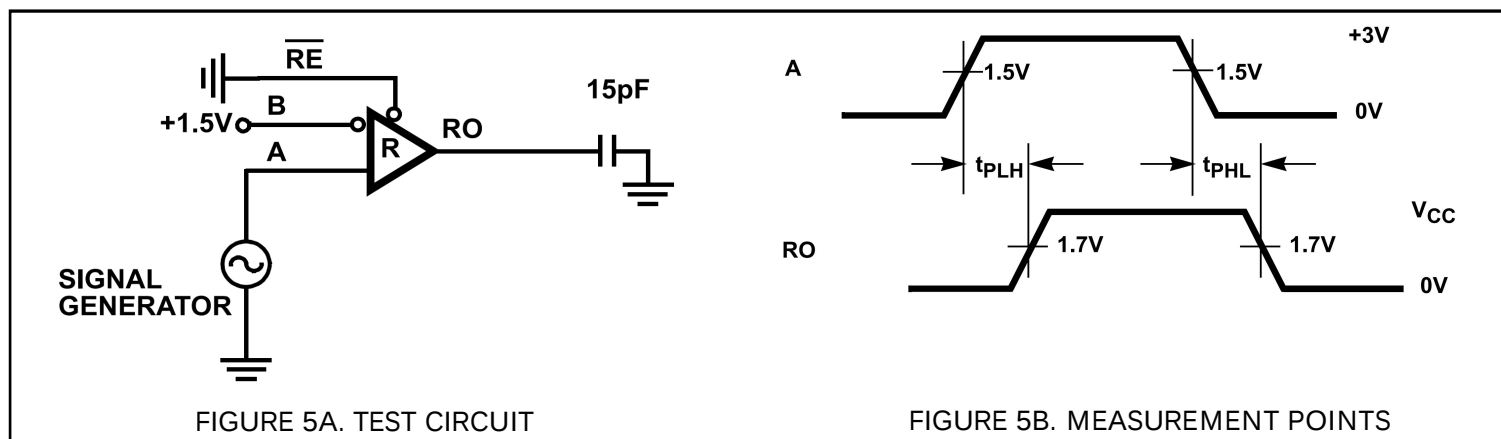
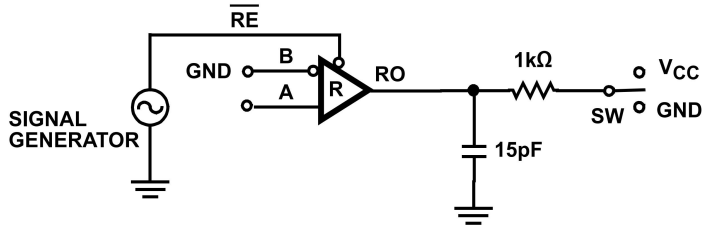


FIGURE 5. RECEIVER PROPAGATION DELAY



Test Circuits and Waveforms (Continued)



PARAMETER	DE	A	SW
t_{HZ}	0	+1.5V	GND
t_{LZ}	0	-1.5V	V _{CC}
t_{ZH} (Note 7)	0	+1.5V	GND
t_{ZL} (Note 7)	0	-1.5V	V _{CC}
$t_{HZ}(SHDN)$ (Note 10)	0	+1.5V	GND
$t_{LZ}(SHDN)$ (Note 10)	0	-1.5V	V _{CC}

FIGURE 6A. TEST CIRCUIT

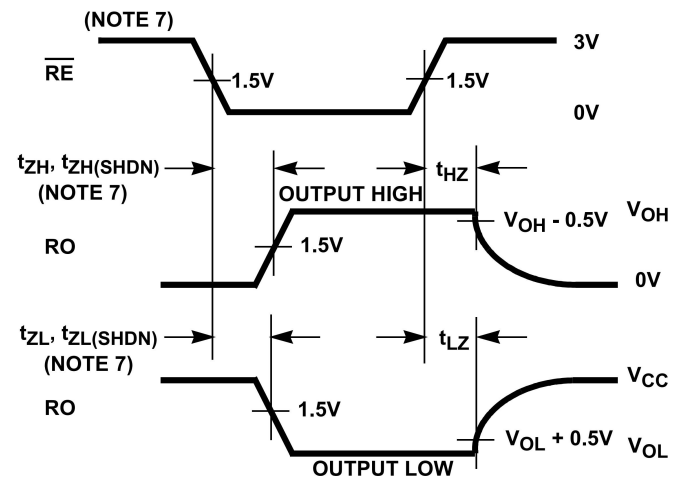
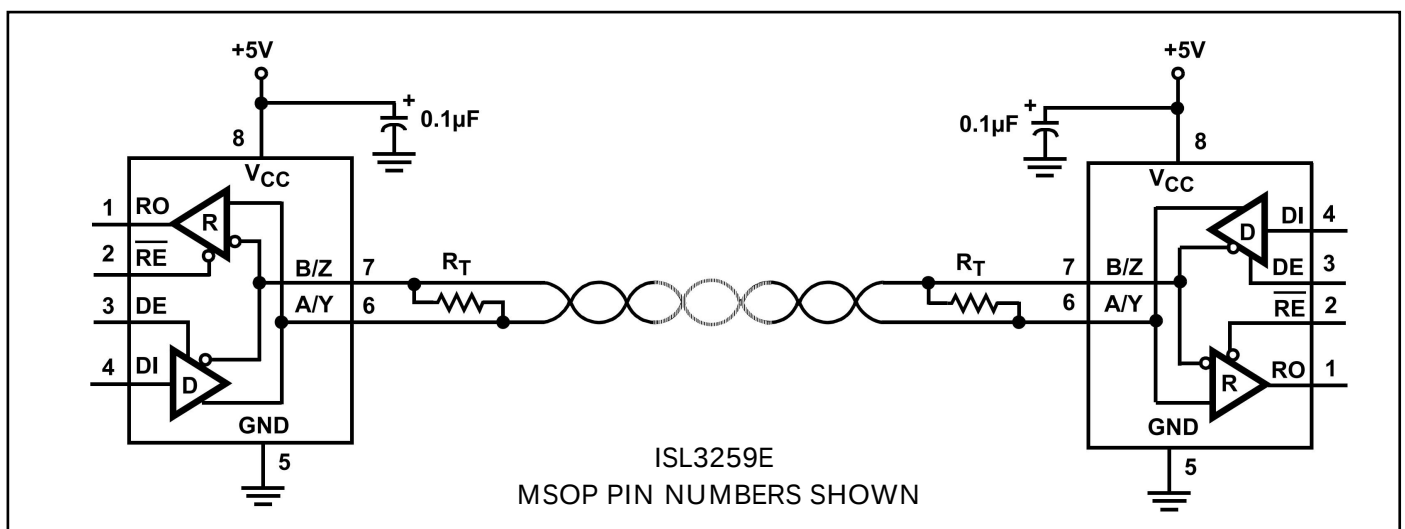


FIGURE 6B. MEASUREMENT POINTS

FIGURE 6. RECEIVER ENABLE AND DISABLE TIMES

Typical Operating Circuit





ORDERING INFORMATION

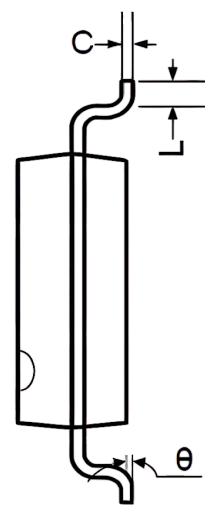
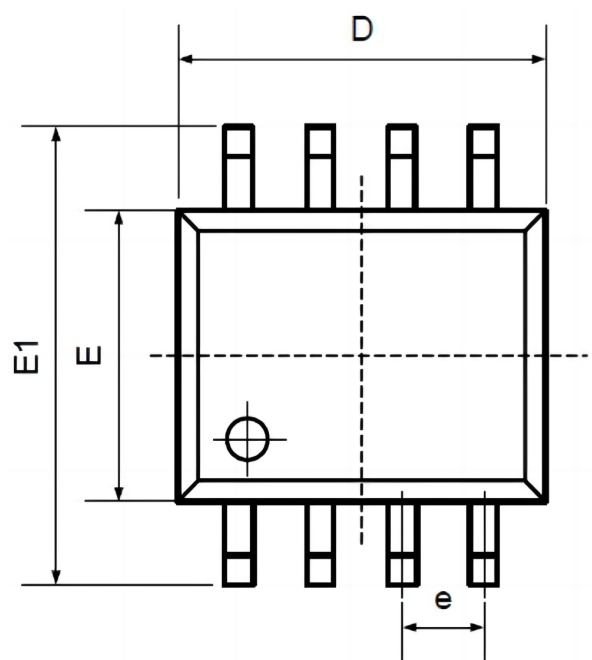
Order Number	Package	Package Quantity	Marking On The park	Temperature
ISL3259EIBZ-T-TUDI	SOP8	Tape,Reel,2500	3259EIBZ	-40°C to +85°C
ISL3259EIUZ-T-TUDI	MSOP8	Tape,Reel,2500	3259Z	

Revision history

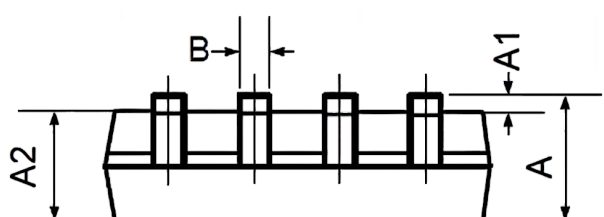
	Date	Revision	Page
V1.0	2020/1	New	1-9
V1.1	2025-4	Update model and PDF template	1-17



Package SOP8

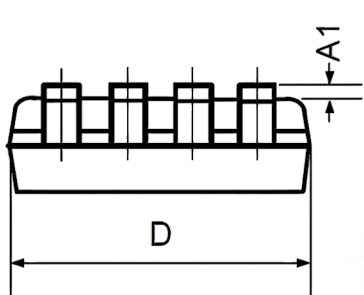
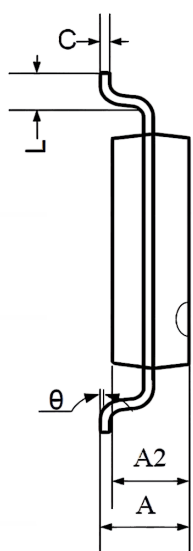
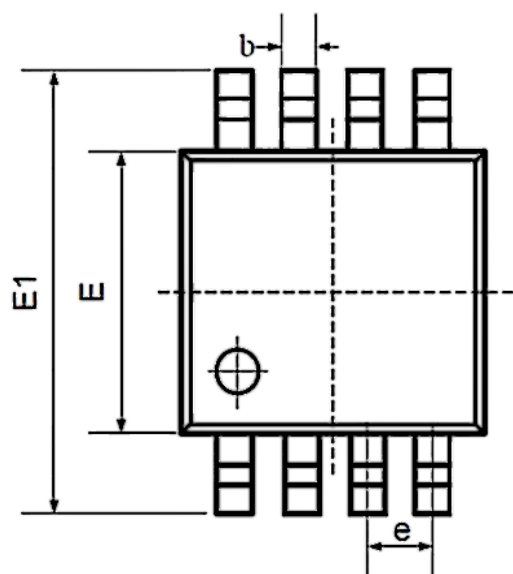


Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	1.350	1.750	0.053	0.069
A1	0.100	0.250	0.004	0.010
A2	1.350	1.550	0.053	0.061
B	0.330	0.510	0.013	0.020
C	0.190	0.250	0.007	0.010
D	4.780	5.000	0.188	0.197
E	3.800	4.000	0.150	0.157
E1	5.800	6.300	0.228	0.248
e	1.270TYP		0.050TYP	
L	0.400	1.270	0.016	0.050
θ	0°	8°	0°	8°





Package MSOP8



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.800	1.200	0.031	0.047
A1	0.000	0.200	0.000	0.008
A2	0.760	0.970	0.030	0.038
b	0.30 TYP		0.012 TYP	
C	0.15 TYP		0.006 TYP	
D	2.900	3.100	0.114	0.122
e	0.65 TYP		0.026 TYP	
E	2.900	3.100	0.114	0.122
E1	4.700	5.100	0.185	0.201
L	0.410	0.650	0.016	0.026
θ	0°	6°	0°	6°



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